

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/784,037 OZAWA ET AL.	
		Examiner Timothy L Rude	Art Unit 2883	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,614,496	09-2003	Song et al.	349/114
	B	US-6,195,140	02-2001	Kubo et al.	349/44
	C	US-6,710,827	03-2004	Kubo et al.	349/55
	D	US-6,281,952	08-2001	Okamoto et al.	349/12
	E	US-6,563,554	05-2003	Okamoto et al.	349/12
	F	US-6,570,634	05-2003	Kim, Yong-Beom	349/107
	G	US-6,657,689	12-2003	Baek, Heum-II	349/114
	H	US-6,580,480	06-2003	Baek et al.	349/114
	I	US-6,532,045	03-2003	Chung et al.	349/43
	J	US-2002/0033918	03-2002	Shigeno et al.	349/114
	K	US-6,542,209	04-2003	Kim et al.	349/106
	L	US-2002/0118323	08-2002	Itou et al.	349/113
	M	US-2001/0046014	11-2001	Ohtake et al.	349/114

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.